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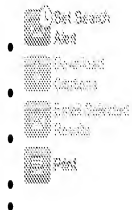
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SOS/SOI Technology Conference, 1989., 1989 IEEE
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Nagai, T.; Numata, K.; Ogihara, M.; Shimizu, M.; Imai, K.; Hara, T.; Yoshida, M.; Saito, Y.; Asao, Y.; Sawada, S.; Fujii, S.;
Solid-State Circuits, IEEE Journal of
 Volume: 26 , Issue: 11
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Solid-State Circuits Conference, 1989. Digest of Technical Papers. 36th ISSCC., 1989 IEEE International

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Li, Hong; Hu, Jianping; Zhang, Cheng;

Circuits and Systems, 2006. MWSCAS '06. 49th IEEE International Midwest Symposium on

Volume: 1

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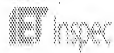
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